Application/Control No.	Applicant(s)/Patent under Reexamination
10/613,977	MIYAWAKI ET AL.
Examiner	Art Unit
Bena Miller	3725

	SEARCHED				
Class	Subclass	Date	Examiner		
229	125.22	10/24/2005	ВВМ		
	117.25				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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